EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|----------|------|--|---|---------------------|---------|------------------|
| L2 | 1688 | 713/193.ccls | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/27 09:10 |
| L3 | 7 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same test near scan same security | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/27 09:15 |
| L4 | 1429 | 714/726.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/27 09:15 |
| L5 | . 20 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (scan near test) and ((secur\$5 or protect\$4) same (sensitive or password or key)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON · | 2007/02/27 09:15 |
| L6 | 4 | I4 and I5 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/27 09:17 |
| L7 | 2 | l2 and l5 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/27 09:17 |
| S1 | 1133 | "integrated circuit" same "scan test" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/26 13:59 |
| S3 | 4 | "integrated circuit" same "scan test" same security | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON . | 2007/02/26 14:07 |
| S4 | 5 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same "scan test" same security | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/26 14:22 |

EAST Search History

| S5 | 1 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same set\$1scan same security | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/26 14:23 |
|-----|------|--|---|-----|----|------------------|
| S6 | 2 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same boundary\$1scan same security | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/26 16:02 |
| S8 | 7 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (test near scan) same security | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/26 16:03 |
| S10 | 1 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (set near scan) same security | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/26 16:04 |
| S11 | . 11 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (set near scan) and ((secur\$5 or protect\$4) same (sensitive or password or key)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/26 16:05 |
| S13 | 20 | ("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "compufer chip") same (scan near test) and ((secur\$5 or protect\$4) same (sensitive or password or key)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2007/02/27 09:15 |

2/27/07 9:34:18 AM C:\Documents and Settings\eshiferaw\My_Documents\EAST\Workspaces\10667021.wsp

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